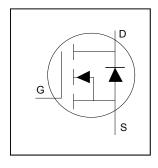
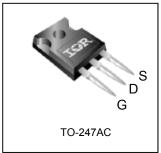


V _{DSS}	60V
R _{DS(on)} typ.	2.1m $Ω$
max.	2.5m Ω
D (Silicon Limited)	270A①
D (Package Limited)	195A





G	D	S
Gate	Drain	Source

Applications

- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free

Base Part Number	Package Type	Standard	Orderable Part Number	
		Form	Quantity	
IRFP3006PbF	TO-247	Tube	25	IRFP3006PbF

Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	270①	Α
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V(Silicon Limited)	190①	
I_D @ T_C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Wire Bond Limited)	195	
I _{DM}	Pulsed Drain Current ②	1080	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	375	W
	Linear Derating Factor	2.5	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
dv/dt	Peak Diode Recovery ④	10	V/ns
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10lbf.in (1.1N.m)	

Avalanche Characteristics

E _{AS (Thermally limited)}	Single Pulse Avalanche Energy ③	320	mJ
I _{AR}	Avalanche Current ②	See Fig. 14, 15, 22a, 22b	Α
E _{AR}	Repetitive Avalanche Energy ®		mJ

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ®		0.4	
$R_{ heta CS}$	Case-to-Sink, Flat Greased Surface	0.24		°C/W
$R_{ heta JA}$	Junction-to-Ambient		40	



Static @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	60			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.07		V/°C	Reference to 25°C, I _D = 5mA ²
R _{DS(on)}	Static Drain-to-Source On-Resistance		2.1	2.5	mΩ	V _{GS} = 10V, I _D = 170A ⑤
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
I _{DSS}	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 60V, V_{GS} = 0V$
				250		$V_{DS} = 60V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100		$V_{GS} = -20V$
R_G	Internal Gate Resistance		2.0		Ω	

Dynamic @ T_J = 25°C (unless otherwise specified)

	J = 20 0 (dilicos otrici wisc specifica)		1			
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	280			S	$V_{DS} = 25V, I_{D} = 170A$
Q_g	Total Gate Charge	—	200	300		I _D = 170A
Q_{gs}	Gate-to-Source Charge	—	37			V _{DS} =30V
Q_{gd}	Gate-to-Drain ("Miller") Charge		60		IIC	V _{GS} = 10V ⑤
Q _{sync}	Total Gate Charge Sync. (Q _g - Q _{gd})		140			$I_D = 170A$, $V_{DS} = 0V$, $V_{GS} = 10V$
$t_{d(on)}$	Turn-On Delay Time		16			$V_{DD} = 39V$
t _r	Rise Time		182		no	I _D = 170A
$t_{d(off)}$	Turn-Off Delay Time		118		ns	$R_G = 2.7\Omega$
t _f	Fall Time		189			V _{GS} = 10V ⑤
C _{iss}	Input Capacitance		8970			$V_{GS} = 0V$
Coss	Output Capacitance		1020			$V_{DS} = 50V$
C_{rss}	Reverse Transfer Capacitance		534		рF	f = 1.0 MHz, See Fig. 5
	Effective Output Capacitance		1480		рг	$V_{GS} = 0V$, $V_{DS} = 0V$ to 48V \bigcirc
	(Energy Related)					See Fig. 11
C _{oss} eff. (TR)	Effective Output Capacitance		1920			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 48V $
	(Time Related)					

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)			257①	_	MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ②			1028		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	٧	$T_J = 25^{\circ}C$, $I_S = 170A$, $V_{GS} = 0V$ 4
t _{rr}	Reverse Recovery Time		44		ns	T _J = 25°C
			48			T _J = 125°C
Q_{rr}	Reverse Recovery Charge		63		nC	$T_J = 25^{\circ}C$ $V_R = 51V$,
			77			$T_J = 125^{\circ}C$ $I_F = 170A$ $di/dt = 100A/\mu s$ §
I _{RRM}	Reverse Recovery Current		2.4		Α	T _J = 25°C

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 195A.Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- ② Repetitive rating; pulse width limited by max. Junction temperature.
- ③ Limited by T_{Jmax} , starting T_J = 25°C, L = 0.022mH, R_G = 50 Ω , I_{AS} = 170A, V_{GS} =10V. Part not Recommended for use above this value.
- ④ ISD ≤ 170A, di/dt ≤ 1360A/ μ s, V_{DD} ≤ $V_{(BR)DSS}$, T_{J} ≤ 175°C.
- ⑤ Pulse width $\leq 400\mu s$; duty cycle $\leq 2\%$.
- \odot Coss eff. (TR) is a fixed capacitance that gives the same charging time as Coss while V_{DS} is rising from 0 to 80% V_{DSS} .
- \odot Coss eff. (ER) is a fixed capacitance that gives the same energy as Coss while V_{DS} is rising from 0 to 80% V_{DSS} .
- * All spec data and curves based on (TO-220 Pak -IRFB3006PbF) Datasheet.



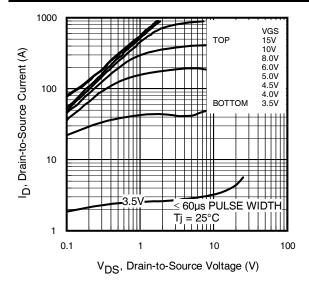


Fig 1. Typical Output Characteristics

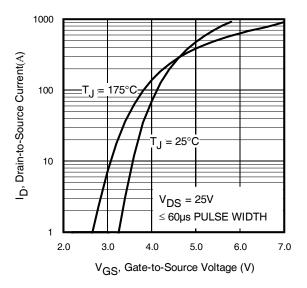


Fig 3. Typical Transfer Characteristics

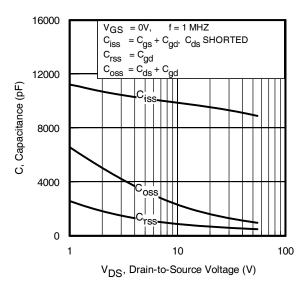


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

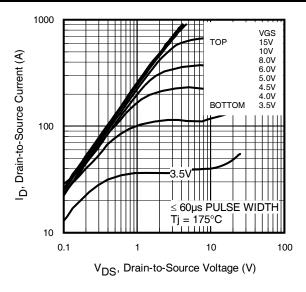


Fig 2. Typical Output Characteristics

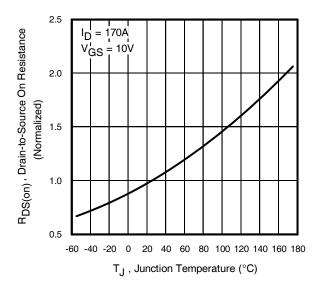


Fig 4. Normalized On-Resistance vs. Temperature

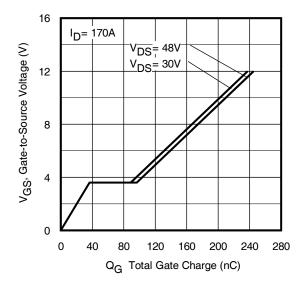


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



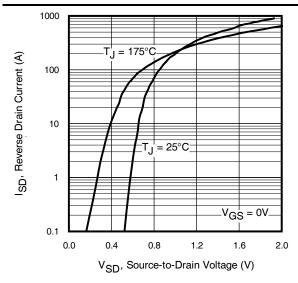


Fig 7. Typical Source-to-Drain Diode Forward Voltage

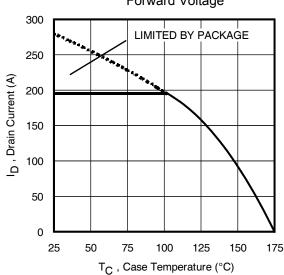


Fig 9. Maximum Drain Current vs. Case Temperature

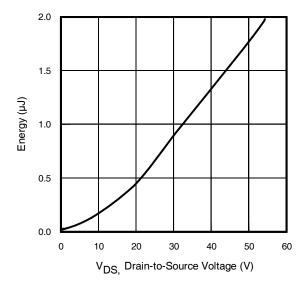


Fig 11. Typical Coss Stored Energy

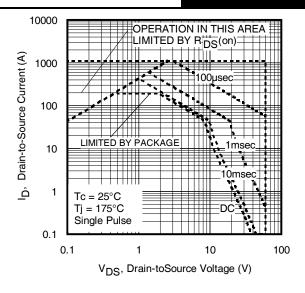


Fig 8. Maximum Safe Operating Area

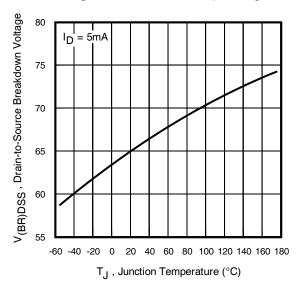


Fig 10. Drain-to-Source Breakdown Voltage

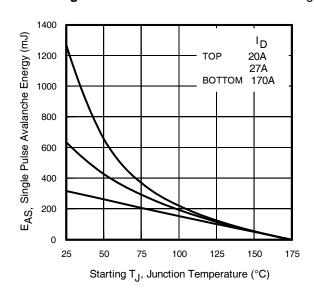


Fig 12. Maximum Avalanche Energy vs. Drain Current

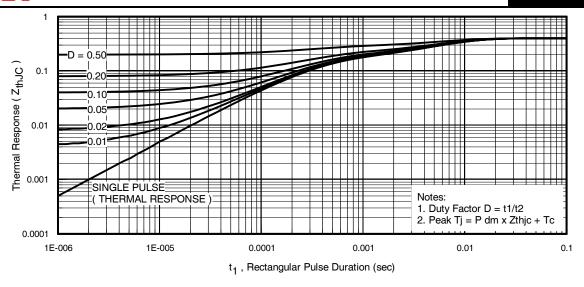


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

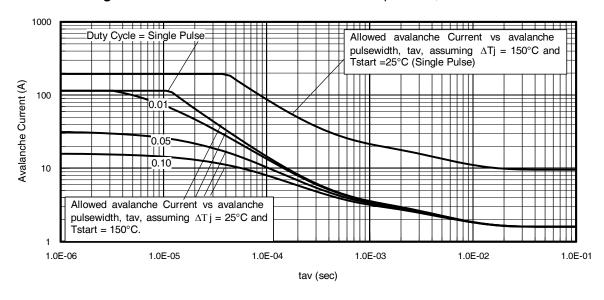


Fig 14. Typical Avalanche Current vs. Pulsewidth

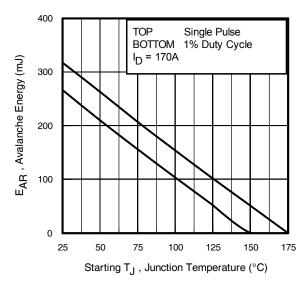


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature
- far in excess of Tjmax. This is validated for every part type.

 2. Safe operation in Avalanche is allowed as long as Tjmax is not
- exceeded.

 3. Equation below based on circuit and waveforms shown in Figures
- 4. P_{D (ave)} = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed Tjmax (assumed as 25°C in Figure 14, 15).
 - t_{av} = Average time in avalanche.
 - D = Duty cycle in avalanche = tav ·f
 - $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



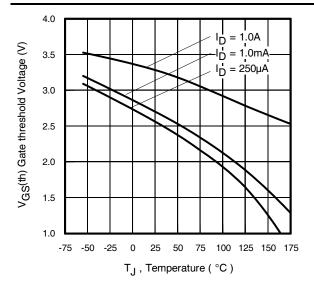


Fig. 16 Threshold Voltage vs. Temperature

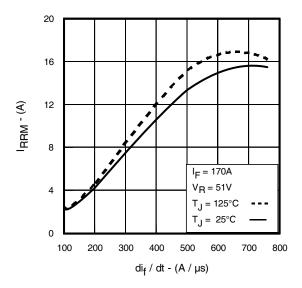


Fig 18. Typical Recovery Current vs. di_f/dt

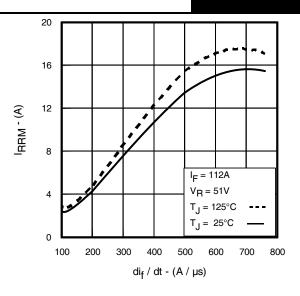


Fig. 17 Typical Recovery Current vs. di_f/dt

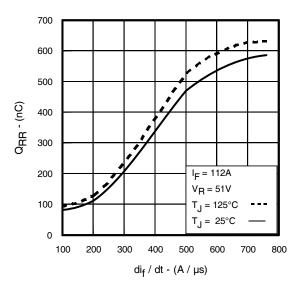


Fig 19. Typical Stored Charge vs. di_f/dt

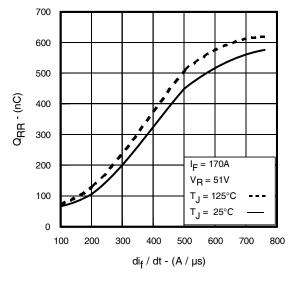
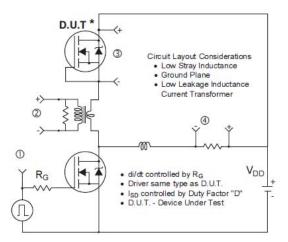
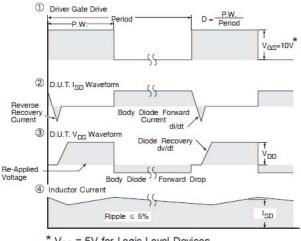


Fig 20. Typical Stored Charge vs. di_f/dt







^{*} Reverse Polarity of D.U.T for P-Channel

* V_{GS} = 5V for Logic Level Devices

Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

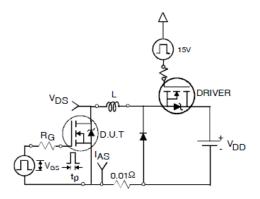


Fig 22a. Unclamped Inductive Test Circuit

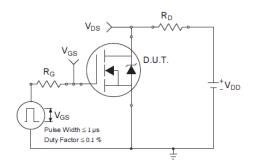


Fig 23a. Switching Time Test Circuit

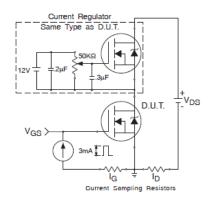


Fig 24a. Gate Charge Test Circuit

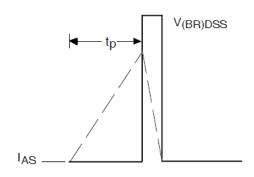


Fig 22b. Unclamped Inductive Waveforms

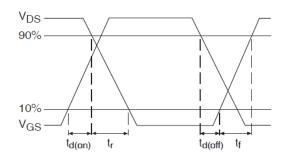


Fig 23b. Switching Time Waveforms

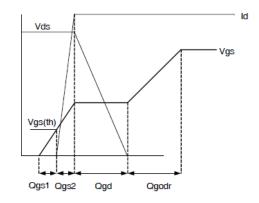
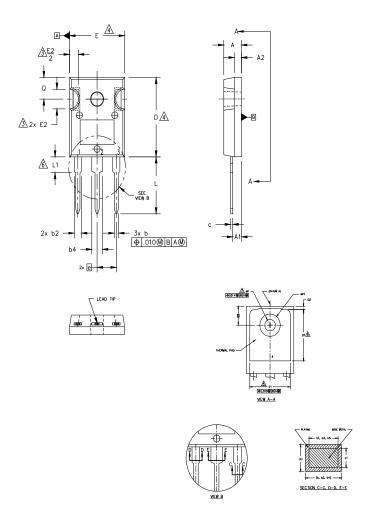


Fig 24b. Gate Charge Waveform



TO-247AC Package Outline (Dimensions are shown in millimeters (inches))



NOTES:

DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M 1994.

2. DIMENSIONS ARE SHOWN IN INCHES.

CONTOUR OF SLOT OPTIONAL.

DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED .005" (0.127)

PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

5 THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS D1 & E1.

LEAD FINISH UNCONTROLLED IN L1.

ØP TO HAVE A MAXIMUM DRAFT ANGLE OF 1.5 * TO THE TOP OF THE PART WITH A MAXIMUM HOLE
DIAMETER OF .154 INCH.

8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-247AC .

SYMBOL	INC	HES	MILLIM	ETERS]
	MIN.	MAX.	MIN.	MAX.	NOTES
A	.183	.209	4.65	5.31	
A1	.087	.102	2.21	2.59	
A2	.059	.098	1.50	2.49	
ь	.039	.055	0.99	1.40	
ь1	.039	.053	0.99	1.35	
b2	.065	.094	1.65	2.39	
b3	.065	.092	1.65	2.34	
b4	.102	.135	2.59	3.43	
b5	.102	.133	2.59	3.38	
c	.015	.035	0.38	0.89	
c1	.015	.033	0.38	0.84	
D	.776	.815	19.71	20.70	4
D1	.515	-	13.08	-	5
D2	.020	.053	0.51	1.35	
E	.602	.625	15.29	15.87	4
E1	.530	-	13.46	-	
E2	.178	.216	4.52	5.49	
e	.215	BSC	5.46	BSC]
Øk	.0	10	0.	25	
L	.559	.634	14.20	16.10	
L1	.146	.169	3.71	4.29]
øP	.140	.144	3.56	3.66	
øP1	-	.291	-	7.39	
Q	.209	.224	5.31	5.69]
S	.217	BSC	5.51	BSC	

LEAD ASSIGNMENTS

<u>HEXFET</u>

1.- GATE 2.- DRAIN 3.- SOURCE

4.- DRAIN

IGBTs, CoPACK

1.- GATE
2.- COLLECTOR
3.- EMITTER
4.- COLLECTOR

DIODES

1.- ANODE/OPEN 2.- CATHODE

3 - ANODE

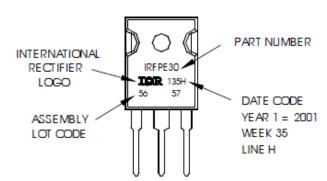
TO-247AC Part Marking Information

EXAMPLE: THIS IS AN IRFPE30

WITH ASSEMBLY LOT CODE 5657

ASSEMBLED ON WW 35, 2001 IN THE ASSEMBLY LINE "H"

Note: "P" in assembly line position indicates "Lead-Free"



TO-247AC package is not recommended for Surface Mount Application.

TO-247AC package is not recommended for Surface Mount Application.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification information[†]

	Industrial				
Qualification level	(per JEDEC JESD47F) ^{††}				
Moisture Sensitivity Level	TO-247AC N/A				
RoHS compliant	Yes				

† Qualification standards can be found at International Rectifier's web site http://www.irf.com/product-info/reliability



IR WORLD HEADQUARTERS: 101N Sepulveda Blvd, El Segundo, California 90245, USA

To contact International Rectifier, please visit http://www.irf.com/whoto-call/

^{††} Applicable version of JEDEC standard at the time of product release.

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